Unit: mm

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (L^2 - π -MOSIV)

2SJ304

DC-DC Converter, Relay Drive and Motor Drive Applications

• 4-V gate drive

• Low drain-source ON resistance : RDS (ON) = 80 m Ω (typ.)

• High forward transfer admittance $: |Y_{fs}| = 8.0 \text{ S (typ.)}$

• Low leakage current $: I_{DSS} = -100 \,\mu\text{A} \,(\text{max}) \,(V_{DS} = -60 \,\text{V})$

• Enhancement mode : $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	-60	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	-60	٧	
Gate-source voltage		V_{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	-14	А	
	Pulse(Note 1)	I_{DP}	- 56		
Drain power dissipation (Tc = 25°C)		P_{D}	40	W	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

This transistor is an electrostatic-sensitive device.

Please handle with caution.

JEDEC —
JEITA SC-67

2-10R1B

1. GATE 2. DRAIN 3. SOURCE

Weight: 1.9 g (typ.)

TOSHIBA

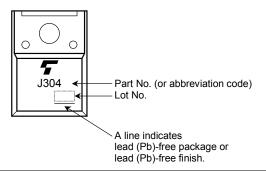
Electrical Characteristics (Ta = 25°C)

Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = -60 V, V _{GS} = 0 V	_	_	-100	μΑ
Drain-source br voltage	eakdown	V _{(BR) DSS}	I _D = -10 mA, V _{GS} = 0 V	-60	_	_	V
Gate threshold v	roltage	V _{th}	V _{DS} = -10 V, I _D = -1 mA	-0.8	_	-2.0	V
Drain aguras Ol	N resistance	_	V _{GS} = -4 V, I _D = -5 A	_	130	190	0
Drain-source ON resistance		R _{DS} (ON)	V _{GS} = -10 V, I _D = -7 A	_	80	120	mΩ
Forward transfer	admittance	Y _{fs}	V _{DS} = -10 V, I _D = -7 A	5.0	8.0	_	S
Input capacitano	:e	C _{iss}		_	1200	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = -10 V, V _{GS} = 0 V, f = 1 MHz	_	220	_	pF
Output capacita	nce	C _{oss}		_	550	_	
Switching time	Rise time	t _r	$V_{GS} \stackrel{OV}{\longrightarrow} I_{D} = -7A$ $V_{CS} \stackrel{OV}{\longrightarrow} R_{L} = 4.3\Omega$ $V_{DD} = -30V$	ı	20	ı	
	Turn-on time	t _{on}		ı	30	ı	ns
	Fall time	t _f		_	25	_	
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm W} = 10 \mu \rm s$	_	100	_	
Total gate charge (Gate-source plus gate-drain)		Qg			45		
Gate-source charge		Q_{gs}	$V_{DD} \approx -48 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -14 \text{ A}$		30	_	nC
Gate-drain ("miller") charge		Q_{gd}			15	_	

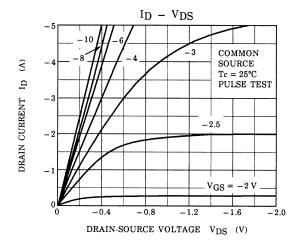
Source-Drain Ratings and Characteristics (Ta = 25°C)

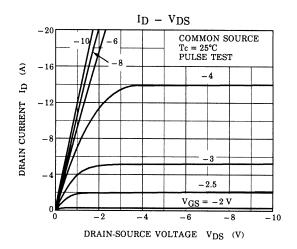
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	-	_	_	-14	Α
Pulse drain reverse current (Note 1)	I _{DRP}	1	_	_	-56	Α
Forward voltage (diode)	V_{DSF}	$I_{DR} = -14 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.7	V
Reverse recovery time	t _{rr}	I _{DR} = -14 A, V _{GS} = 0 V	1	110		ns
Reverse recovery charge	Qrr	dI_{DR} / $dt = 50 \text{ A}$ / μs	1	0.18	1	μC

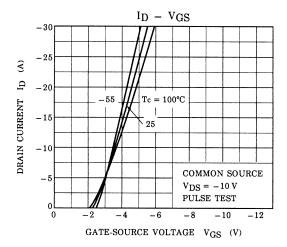
Marking

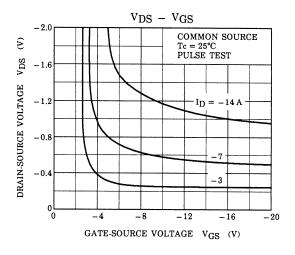


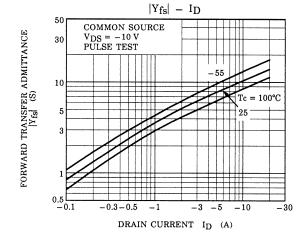
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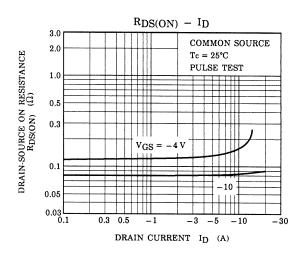




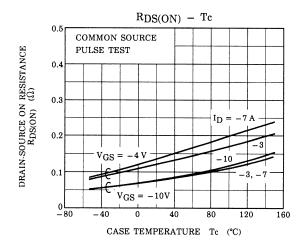


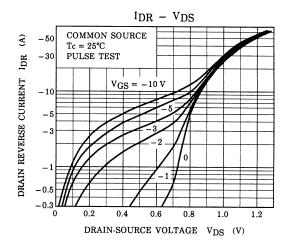


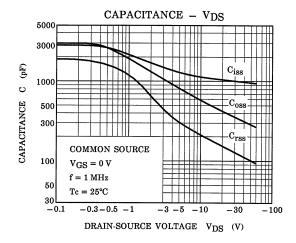


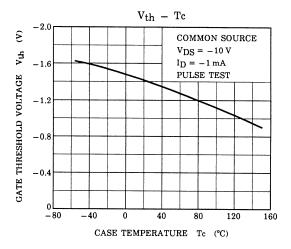


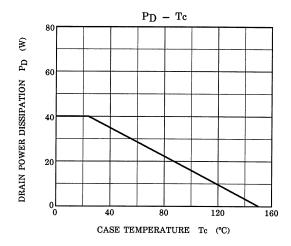
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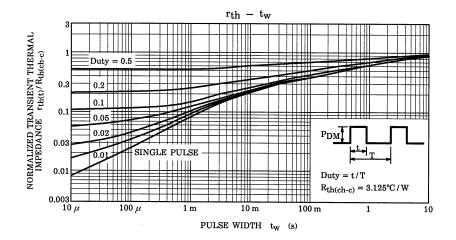


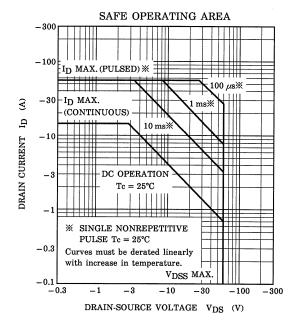












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